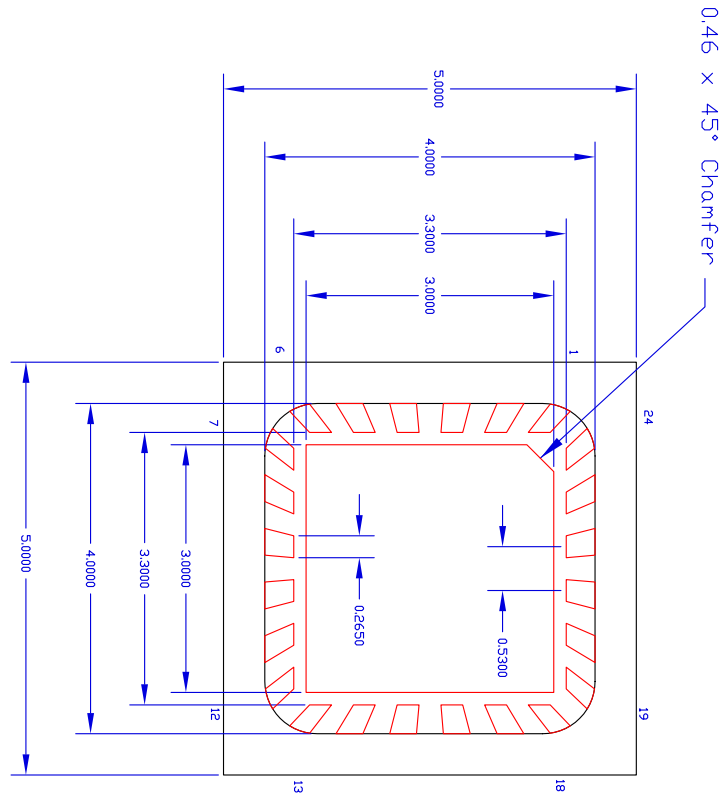
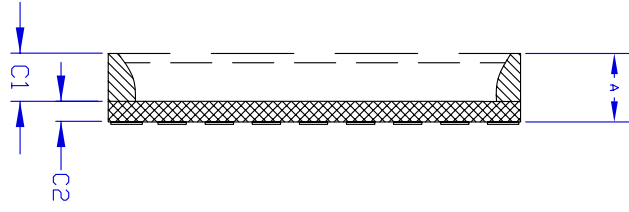


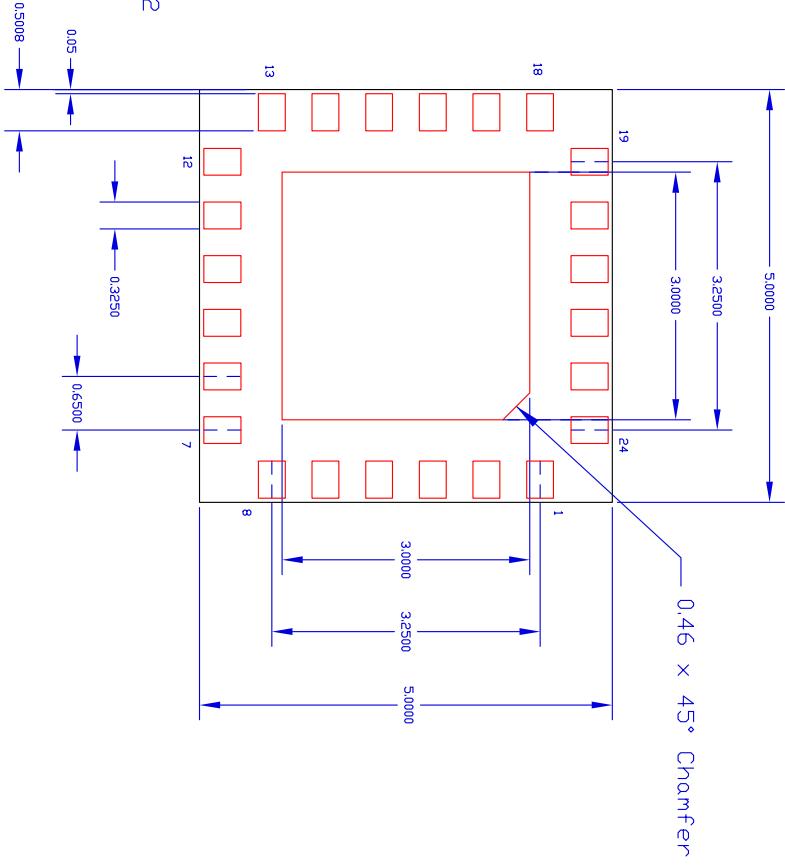
TOP VIEW



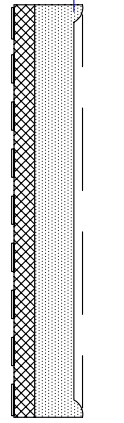
SIDE VIEW



BOTTOM VIEW



Cavity wall
variance
0.05~0.15



SIDE VIEW

HEIGHT TABLE			
SERIES	C1	C2	A
A-QFN	0.63	0.27	0.90
A-TQFN	0.38	0.27	0.65
TOL	+/- 0.10	+/- 0.05	+/- 0.15

OTHER SIZES AVAILABLE

THIS DOCUMENT AND THE TECHNOLOGY IT REPRESENT ARE, AND SHALL REMAIN, THE PROPRIETARY PROPERTY OF MIRROR SEMICONDUCTOR. THIS DOCUMENT IS PROVIDED TO RECIPIENT ON A CONFIDENTIAL BASIS WITH THE RECIPIENT'S AGREEMENT THAT IT WILL NOT REPRODUCE, COPY, LOAN, EXHIBIT NOR USE, EITHER IN WHOLE OR IN PART, THE DOCUMENT OR ITS CONTENT, EXCEPT IN THE LIMITED WAY AND FOR ITS PRIVATE USE AS PERMITTED BY MIRROR SEMICONDUCTOR.

Note:

- Organic substrate
- Cavity Dam: Hysol FP4451TD
- Pads: Cu/Ni/Au
- Copper Thickness: 12µm~18µm (0.5~0.7mil)
- Bonding Pad Gold Thickness: 1.3µm (50 micro-inch)
- PCB Pads Gold Thickness: 0.13µm (5 micro-inch)
- Nickel Thickness: 38µm (150 micro-inch)
- All Dimensions Are mm

TOLERANCES UNLESS NOTED:		APPROVALS		DATE	
X.XX	±			11/29/08	
X.XXX	±				
X.XXXX	±				
ALL DIMENSIONS ARE IN:		DRAWN		TA	
INCHES <input type="checkbox"/> MILLIMETERS <input checked="" type="checkbox"/>		ENG			
THIRD ANGLE PROJECTION:		MFG		TITLE	
2A				24-LEAD 5MM P=0.65MM	
CUST		SCALE		A-QFN (AIR) OPEN CAVITY	
REVISED		NONE		SIZE	
		A		DRAWING NO.	
		462410		REV	
		DO NOT SCALE DRAWING		A	
		SHEET 1 OF 1			

